2.5V Drive Nch+SBD MOSFET **US6U37**

Structure

Silicon N-channel MOSFET/ Schottky barrier diode

● Features

- 1) Nch MOSFET and schottky barrier diode are put in TUMT6 package.
- 2) High-speed switching, Low On-resistance.
- 3) Low voltage drive (2.5V drive).
- 4) Built-in Low VF schottky barrier diode.

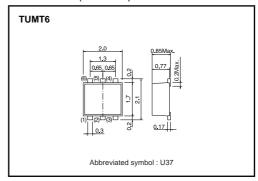
Applications

Switching

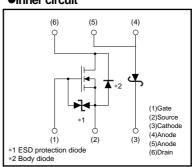
Package specifications

	Package	Taping
Туре	Code	TR
	Basic ordering unit (pieces)	3000
US6U37		0

● **Dimensions** (Unit: mm)



•Inner circuit



● Absolute maximum ratings (Ta=25°C)

<MOSFET>

Parameter		Symbol	Limits	Unit
Drain-source voltage		V _{DSS}	30	V
Gate-source voltage		Vgss	±12	V
Danie accept	Continuous	lo	±1.5	Α
Drain current	Pulsed	I _{DP} *1	±6.0	A
Source current	Continuous	Is	0.6	Α
(Body diode)	Pulsed	I _{SP} *1	6.0	Α
Channel temperature		Tch	150	°C
Power dissipation		P _D *2	0.7	W / ELEMENT

*1 Pw≤10μs, Duty cycle≤1% *2 Mounted on a ceramic board

<Di>

Parameter	Symbol	Limits	Unit
Repetitive peak reverse voltage	V _{RM}	25	V
Reverse voltage	VR	20	V
Forward current	lF	0.7	Α
Forward current surge peak	IFSM *1	10	A
Junction temperature	Tj	150	°C
Power dissipation	P _D *2	0.5	W / ELEMENT

^{*1 60}Hz • 1cycle *2 Mounted on ceramic board

<MOSFET and Di>

Parameter	Symbol	Limits	Unit	
Power dissipation	P _D *1	1.0	W / TOTAL	
Range of storage temperature	Tstg	-55 to +150	°C	

^{*1} Mounted on a ceramic board

●Electrical characteristics (Ta=25°C)

<MOSFET>

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Gate-source leakage	Igss	_	_	±10	μΑ	V _{GS} =±12V, V _{DS} =0V
Drain-source breakdown voltage	V(BR) DSS	30	-	_	V	ID= 1mA, VGS=0V
Zero gate voltage drain current	IDSS	_	_	1	μΑ	V _{DS} = 30V, V _{GS} =0V
Gate threshold voltage	V _{GS (th)}	0.5	-	1.5	V	V _{DS} = 10V, I _D = 1mA
Otation lands		_	170	240	mΩ	I _D = 1.5A, V _{GS} = 4.5V
Static drain-source on-state resistance	R _{DS (on)} *	_	180	250	mΩ	I _D = 1.5A, V _{GS} = 4V
resistance		_	240	340	mΩ	ID= 1.5A, VGS= 2.5V
Forward transfer admittance	Y _{fs} *	1.5	-	_	S	V _{DS} = 10V, I _D = 1.5A
Input capacitance	Ciss	-	80	_	pF	V _{DS} = 10V
Output capacitance	Coss	_	14	_	pF	V _{GS} =0V
Reverse transfer capacitance	Crss	_	12	_	pF	f=1MHz
Turn-on delay time	t _{d (on)} *	-	7	_	ns	Vpp≒ 15V
Rise time	tr *	_	9	_	ns	ID= 0.75A VGS= 4.5V
Turn-off delay time	t _{d (off)} *	_	15	_	ns	VGS= 4.5V RL≒ 20Ω
Fall time	t _f *	_	6	_	ns	R _G =10Ω
Total gate charge	Qg *	1	1.6	2.2	nC	V _{DD} = 15V, V _{GS} = 4.5V
Gate-source charge	Q _{gs} *	-	0.5		nC	I _D = 1.5A
Gate-drain charge	Q _{gd} *		0.3	_	nC	R _L ≒10Ω, R _G =10Ω

*Pulsed

<Body diode characteristics (Source-drain)>

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Forward voltage	VsD	_	_	1.2	V	I _S = 0.6A, V _{GS} =0V

<Di>

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Forward voltage	VF	_	_	0.49	V	I _F = 0.7A
Reverse current	lr	_	_	200	μΑ	V _R = 20V

•Electrical characteristics curves

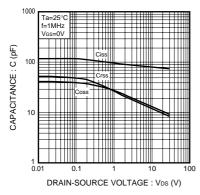


Fig.1 Typical Capacitance vs. Drain-Source Voltage

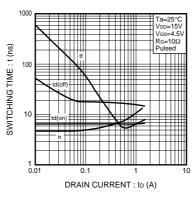


Fig.2 Switching Characteristics

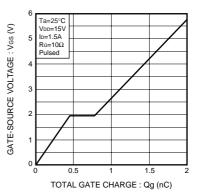


Fig.3 Dynamic Input Characteristics

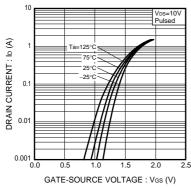


Fig.4 Typical Transfer Characteristics

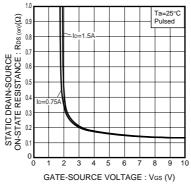


Fig.5 Static Drain-Source On-State Resistance vs. Gate source Voltage

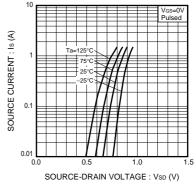


Fig.6 Source Current vs. Source-Drain Voltage

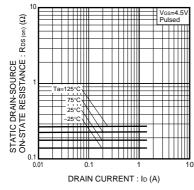


Fig.7 Static Drain-Source On-State Resistance vs. Drain Current (I)

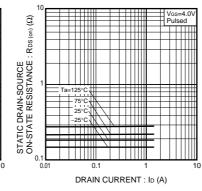


Fig.8 Static Drain-Source On-State Resistance vs. Drain Current (II)

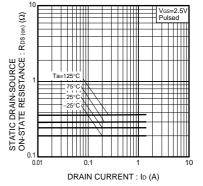
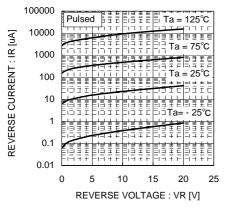


Fig.9 Static Drain-Source On-State Resistance vs. Drain Current (III)



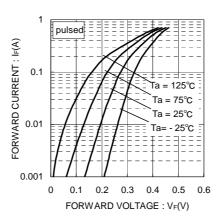


Fig.10 Reverse Current vs. Reverse

Fig.11 Forward Current vs. Forward Voltage

●Measurement circuit

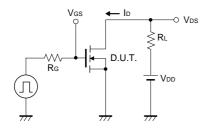


Fig.12 Switching Time Test Circuit

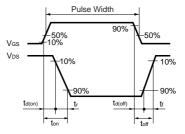


Fig.13 Switching Time Waveforms

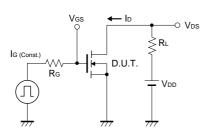


Fig.14 Gate Charge Measurement Circuit

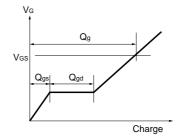


Fig.15 Gate Charge Waveform

●Notice

- 1. SBD has a large reverse leak current compared to other type of diode. Therefore; it would raise a junction temperature, and increase a reverse power loss. Further rise of inside temperature would cause a thermal runaway.
 This built-in SBD has low V_F characteristics and therefore, higher leak current. Please consider enough the surrounding temperature, generating heat of MOSFET and the reverse current.
- 2. This product might cause chip aging and breakdown under the large electrified environment. Please consider to design ESD protection circuit.

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